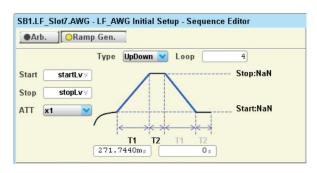
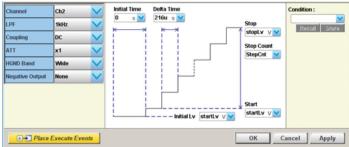
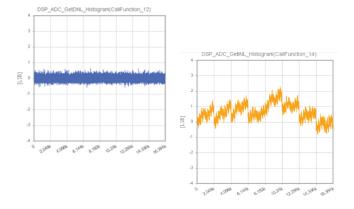


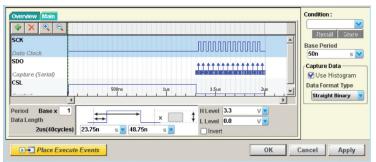
ADC Linearity Test Solution

EVA100 MEASUREMENT SYSTEM









EASY AND HIGH-ACCURACY LINEARITY MEASUREMENT

All-in-one measurement functions and software.

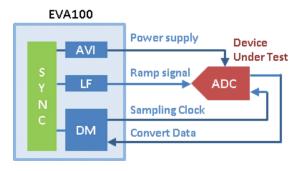
Intuitive application tools.

High-accuracy, high-speed measurement solutions.

■ ADC Linearity Testing

The EVA100 has a measurement module for ADC linearity testing that is optimized for easy and high-accuracy measurements.

Linearity measurement configuration

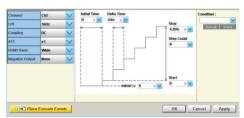


AVI: Voltage current monitor, source module LF: 17-bit linear ramp output, AWG module DM: Digital module, histogram calculation

■ Synchronized Measurement Settings

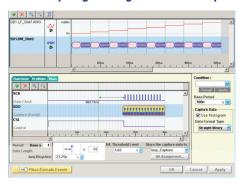
The intuitive GUI makes it easy to set measurement timing and synchronize the hardware, enabling highly repeatable measurements.

Step ramp waveform setting



Setting items START voltage STOP voltage STEP voltage Time interval

AD sampling timing and data output timing



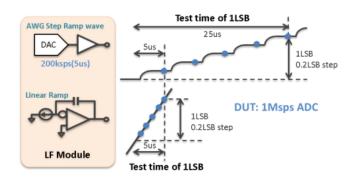
Display step ramp waveform and AD sampling timing on the same GUI for easy-to-check synchronized settings.

Set AD sampling timing and data output timing by timing chart.

■ 17-bit Linear Ramp for High-Speed Measurement

The EVA100 has a linear ramp high-speed measurement function for high-speed sampling of ADCs.

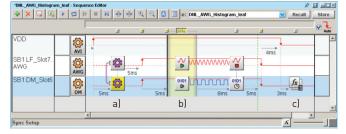
- 17-bit linear ramp signal accuracy
- 14-bit ADC testing



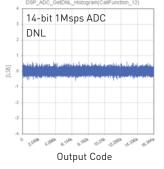
■ Test Sequences Set by Template

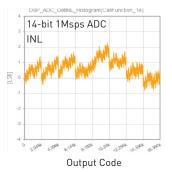
A standard template makes it easy to set measurement conditions.





Report output





■ Specifications

Stepping ramp linearity Linear ramp linearity Linear ramp output period Histogram calculation 15-bit (typ.) 17-bit (typ.) 500 us ~ 500 ms High speed Hardware processing

ADVANTEST®

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